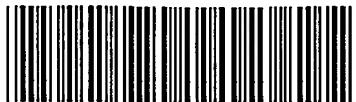


Search Notes**Application/Control No.**

10/759,630

Examiner

Hae M. Hyeon

Applicant(s)/Patent under Reexamination

BOEMMEL ET AL.

Art Unit

2839

SEARCHED

Class	Subclass	Date	Examiner
439	492	4/65	hmh
439	493		
439	495		
439	499		
439	714		
439	710		
439	590		
439	596		
439	937		
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner